NOTES:

1. SUBSTRATE MATERIAL: FUSED SILICA

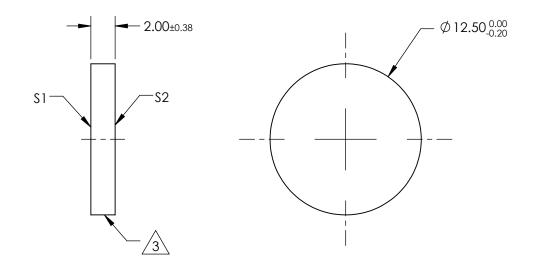
2. COATING (APPLY ACROSS CLEAR APERTURE)

S1: R(abs)= 30% ±5% @ 350nm, 45° AOI R(avg)= 30% ±10% OVER 250 - 450nm, 45° AOI T(abs)= 70% ±5% @ 350nm, 45° AOI T(avg)= 70% ±10% OVER 250 - 450nm, 45° AOI

S2: BBAR (R(avg) <1%, R(abs) <2% OVER 250 - 450nm), 45° AOI

3. EDGES FINE GROUND

4. ROHS COMPLIANT



FOR INFORMATION ONLY: DO NOT MANUFACTURE PARTS TO THIS DRAWING

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE DIMENSIONS ARE FOR REFERENCE ONLY

REV. A	\$1	\$2]			Edmund Optic	C®
SHAPE	PLANO	PLANO					,S
CLEAR APERTURE	Ø10.625	Ø10.625				Ø12.5mm, 30R/70T, UV PLATE BEAMSPL	ITTER
SURFACE QUALITY	60-40	60-40	THIRD ANGLE PROJECTION		TITLE	Ø12.0Hill, OOK, 701, OV 1 L/ (IL DL/ (WO) EITTEK	
SURFACE FLATNESS	1λ	1λ		1			011557
BEVEL	PROTECTED AS NEEDED	PROTECTED AS NEEDED	ALL DIMS IN	mm	DWG NO	48194	SHEET 1 OF 1